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## Solar Cells Reporting Summary

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## Experimental design

| 1. | Dimensions   |              |  |
|----|--|--------------|--|
|    | Area of the tested solar cells   | ∑Yes<br>☐ No | Methods section: 0.1 cm2.  |
|    | Method used to determine the device area   | Yes No       | Methods section: Device area is defined by cross-overlap of the 0.2 cm wide patterned ITO bar and the 0.5 cm wide Al/Cu bar deposited through a shadow mask.                       |
| 2. | Current-voltage characterization   |              |  |
|    | Current density-voltage (J-V) plots in both forward and backward direction   | Yes No       | Fig. 1b  |
|    | Voltage scan conditions<br>For instance: scan direction, speed, dwell times  | Yes No       | Main text: the voltage was scanned both in forward direction from -0.2 V to 1.2 V and reverse direction from 1.2 V to -0.2 V with a scan speed 0.02 V/s                            |
|    | Test environment<br>For instance: characterization temperature, in air or in glove box   | Yes No       | Main text: in N2-filled glove box  |
|    | Protocol for preconditioning of the device before its characterization   | Yes No       | Main text: no preconditioning  |
|    | Stability of the J-V characteristic<br>Verified with time evolution of the maximum power point or with<br>the photocurrent at maximum power point; see ref. 7 for details. | Yes No       | Supplementary Fig. 3: steady-state PCEs were obtained by tracking the maximum power point.   |
| 3. | Hysteresis or any other unusual behaviour  |              |  |
|    | Description of the unusual behaviour observed during the characterization  | Yes No       | Main text: negligible hysteresis and no other unusual behavior   |
|    | Related experimental data  | Yes No       | Not relevant   |
| 4. | Efficiency   |              |  |
|    | External quantum efficiency (EQE) or incident photons to current efficiency (IPCE)   | Yes No       | Fig. 1d.   |
|    | A comparison between the integrated response under<br>the standard reference spectrum and the response<br>measure under the simulator                                      | X Yes        | Main text: the integrated Jsc obtained from the EQE spectra agrees well with the Jsc value obtained from the J–V curves under the simulator within 5% deviation                    |
|    | For tandem solar cells, the bias illumination and bias voltage used for each subcell   | Yes No       | Not relevant.  |
| 5. | Calibration  |              |  |
|    | Light source and reference cell or sensor used for the characterization  | Yes No       | Methods section: light source: a SS-F5-3A solar simulator (Enli Technology CO., Ltd.) for AM 1.5G illumination (100 mW cm-2); reference cell: a standard Si solar cell (SRC-00036) |
|    | Confirmation that the reference cell was calibrated and certified  | Yes No       | Methods section: the reference cell is calibrated and certified by Enli Technology   |

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|    | Calculation of spectral mismatch between the   | X Yes  | 1.017   |
|----|--|--------|---|
|    | reference cell and the devices under test  | No     |   |
| 6. | Mask/aperture  |        |   |
|    | Size of the mask/aperture used during testing  | Yes No | Methods section:non-reflective mask with area of 0.049 cm2 was also used to define the cell area          |
|    | Variation of the measured short-circuit current density with the mask/aperture area  | Yes No | Not relevent  |
| 7. | Performance certification  |        |   |
|    | Identity of the independent certification laboratory that confirmed the photovoltaic performance   | Yes No | The photovoltaic performance of our devices was not confirmed from independent certification laboratories |
|    | A copy of any certificate(s)  Provide in Supplementary Information   | Yes No | Not relevent  |
| 8. | Statistics   |        |   |
|    | Number of solar cells tested   | Yes No | Main text: more than 20 devices for each kind of devices were tested                                      |
|    | Statistical analysis of the device performance   | Yes No | Fig. 1c, Table 1  |
| 9. | Long-term stability analysis   |        |   |
|    | Type of analysis, bias conditions and environmental conditions  For instance: illumination type, temperature, atmosphere  hymidity, encapsulation method, preconditioning temperature. | Yes No | Fig. 5a: a shelf-life test in ambient with 40% - 50% and 75% - 85% RH without any encapsulation           |